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Seok II CHANG

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## U.S. PATENT DOCUMENTS

EXAMINER'S INITIALS	*PATENT NO.	*ISSUE DATE	*INVENTOR NAME	CLASS	SUBCLASS	FILING DATE

## U.S. PATENT APPLICATION PUBLICATIONS

*PATENT APPLN. PUB. NO.	*PUB. DATE	*APPLICANT	CLASS	SUBCLASS

## U.S. PATENT APPLICATIONS

*APPLN. NO.	*FILING DATE	*INVENTOR	CLASS	SUBCLASS

## FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
IFA	JP 2001-501798	02/06/2001	Japan (English Abstract and claims and Japanese Full Text)			X	
IFA	JP 2002-520922	07/09/2002	Japan (English Abstract and claims and Japanese Full Text)			X	

## OTHER ART (Including Author, Title, Date, Pertinent Pages, Publisher, Place of Publication, Etc.)

Japanese Office Action dated June 2, 2006.

EXAMINER

/Freshteh Aghdam/

DATE CONSIDERED

02/15/2007

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